## Notice of References Cited Application/Control No. 10/579,483 Examiner BENYAM KETEMA Applicant(s)/Patent Under Reexamination EICH ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0128191	07-2003	Strasser et al.	345/173
*	В	US-6,282,464	08-2001	Obradovich, Michael L.	701/1
	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р		A			
	q					
6	R					
	s					
	I				100	

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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